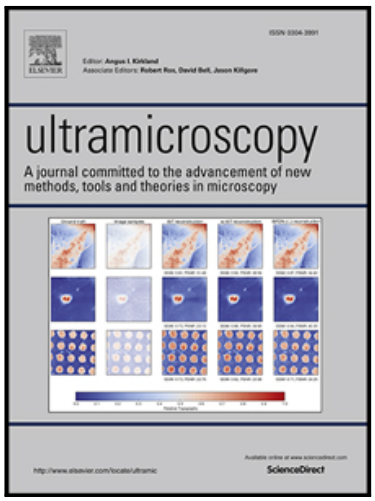

Accuracy and precision of thickness determination from position-averaged convergent beam electron diffraction patterns using a single-parameter metric

J.A. Pollock, M. Weyland, D.J. Taplin, L.J. Allen, S.D. Findlay

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Highlights

- Thickness can be determined by comparing experimental and simulated PACBED patterns.
- Automated comparison using a sum square difference metric is presented in detail.
- The effects of noise, mistilt, surfaces and inelastic scattering are explored.
- While such factors reduce precision, the accuracy is generally high.
- The precision tends to improve for smaller probe-forming aperture angles.